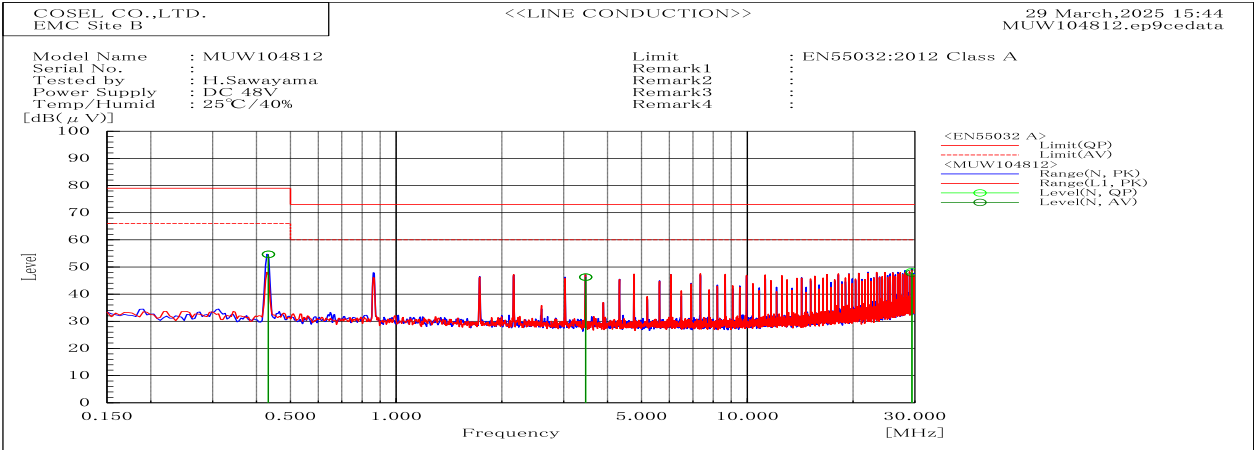
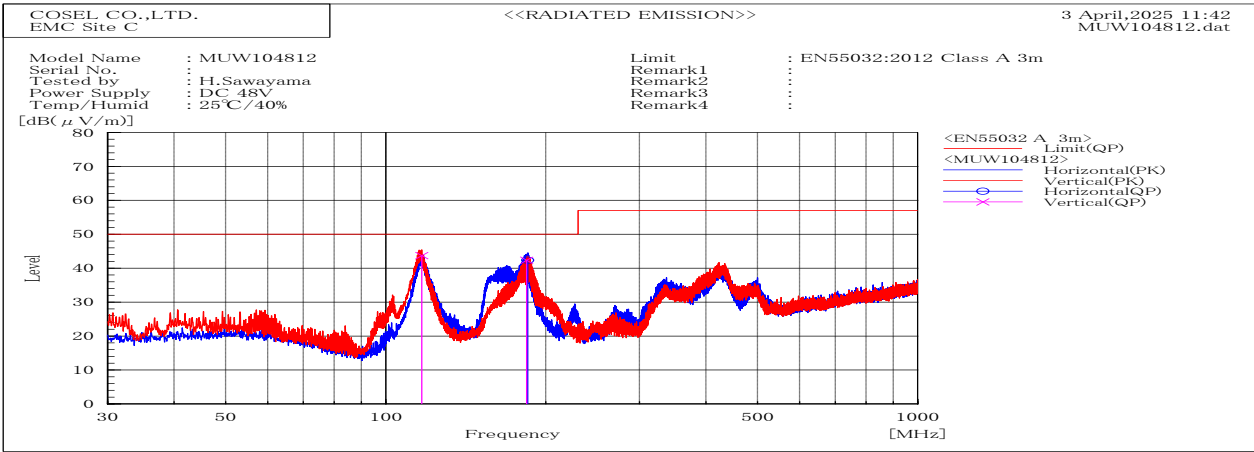


DATA SHEET		Date	03-Apr-25
Model	MUW104812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Sawayama



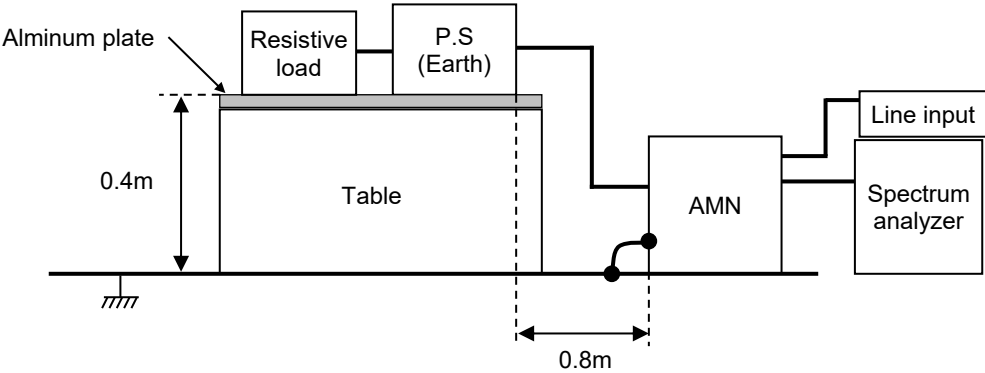
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.433	N	54.7	54.7	79	66	24.3	11.3	Pass	
29.449	N	48.3	47.8	73	60	24.7	12.2	Pass	
3.464	N	46.3	46.3	73	60	26.7	13.7	Pass	



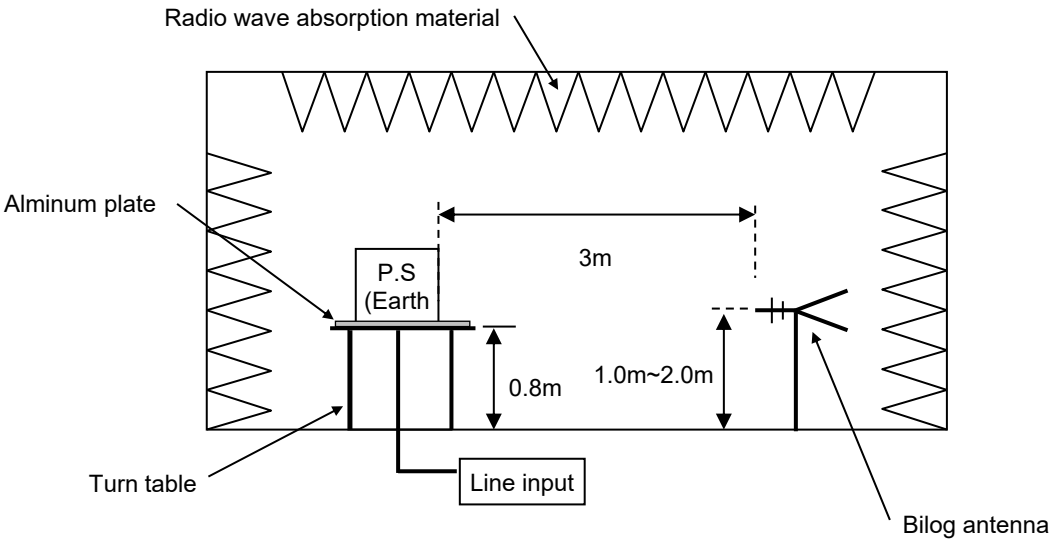
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m) QP	dB(uV/m) QP	dB QP				
116.899	V	Stable	43.7	50	6.3	Pass	119.7	0	
184.022	V	Stable	42.4	50	7.6	Pass	100.2	1.4	
184.877	H	Stable	42.3	50	7.7	Pass	199.7	171.8	

DATA SHEET		Date	03-Apr-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Sawayama

1. Line conduction



2. Radiated emission



Conditions

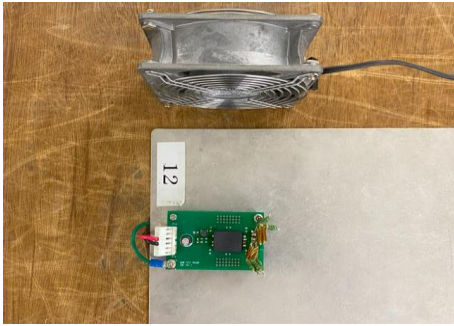
Test : EMI
Model Name: MUW10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

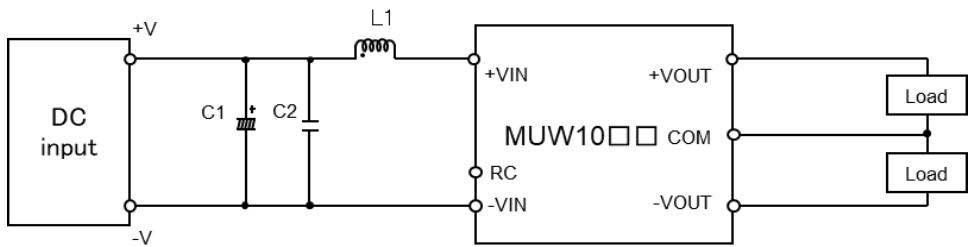


Fig.1 MUW10□□ Testing circuitry

C1 :	MUW1005□	25V 1500 μ F	Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MUW1012□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUW1024□	—	—
	MUW1048□	—	—
C2 :	MUW1005□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUW1012□	25V 10 μ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUW1024□	50V 4.7 μ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUW1048□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUW1005□	5000mA 2.2 μ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUW1012□	3500mA 4.7 μ H	Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING)
	MUW1024□	1600mA 22 μ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)
	MUW1048□	1100mA 47 μ H	Inductor(LQH5BPN470M38 MURATA MANUFACTURING)